

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

te the Application of

Takeshi CHONAN et al.

Group Art Unit: 1773

Application No.: 10/535,234

Filed: June 14, 2005

Docket No.: 123910

For: LAMINATED STRUCTURE FOR SHIELDING AGAINST SOLAR RADIATION

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR § 1.56, the attention of the Patent and Trademark Office is hereby directed to the reference(s) listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- One or more reference cited herein was cited in a counterpart foreign application.
 An English language version of the foreign search report is attached for the Examiner's information. See References 1, 3 and 4.
- Z. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- 3. An English language Abstract of one or more non-English language reference is attached. See Reference 3.
- 4. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office ([http://www.jpo.go.jp]), and is attached is of record in the parent application, but has not been reviewed for accuracy. See Reference 3.
- S. Reference 2 corresponds to reference 4.

Respectfully submitted,

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JAO:JAR/aha

Date: July 19, 2007

OLIFF & BERRIDGE, PLC P.O. Box 19928 Alexandria, Virginia 22320 Telephone: (703) 836-6400 DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461

				Isuyosh	n HOSOKAWA et al.			
				FILING June 21	DATE , 2007			
		U	S. PATEN	T DOCUM	MENTS			
Examiner Initials	Cite No.	Document Number	Date			Name		
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	2	2006/0178524 A1	08/10/2006		Zuber et al.			
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FOREIGN PATENT DOCUMENTS								
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	4	FP 1 676 890 A1	07/05/20	06	EUROPE			
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EXAMINER DATE CONSIDERED								
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Date: July 19, 2007

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